

Baseline ECal update

R. Frey (Oregon) for the ECal group

- Silicon/tungsten concept
- Baseline option: R&D progress
 - Sensors
 - KPiX readout (→ D. Freytag talk)
 - Interconnects
 - (Mechanical design for SiD)
- SiD/CLIC

- Alternative technology choice: MAPS/Therapixel progress (see Marcel Stanitzki talk)

Si/W (baseline) R&D Collaboration

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- KPiX readout chip
- downstream readout
- mechanical design and integration
- detector development
- readout electronics
- readout electronics
- Interconnects: bump bonding, flex cable development

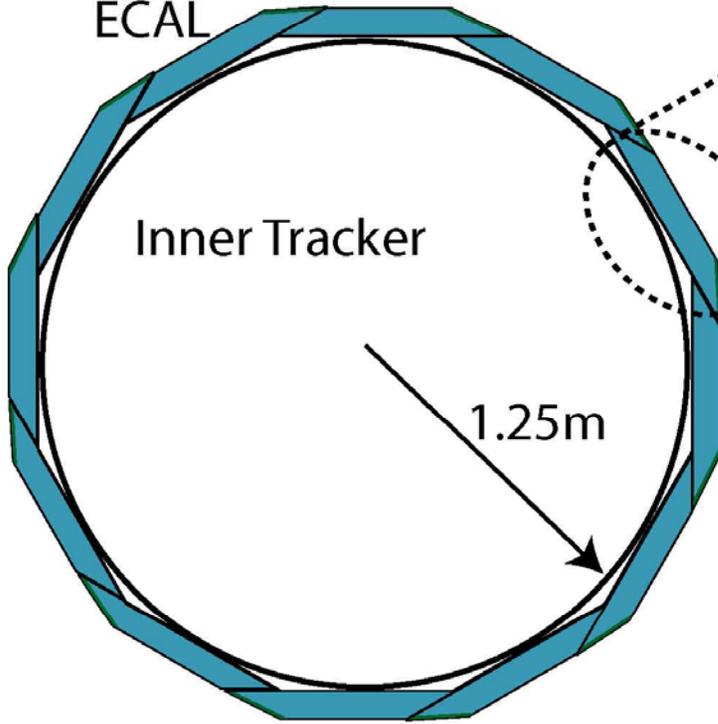
Baseline Silicon-Tungsten ECal

Si-W Calorimeter Concept

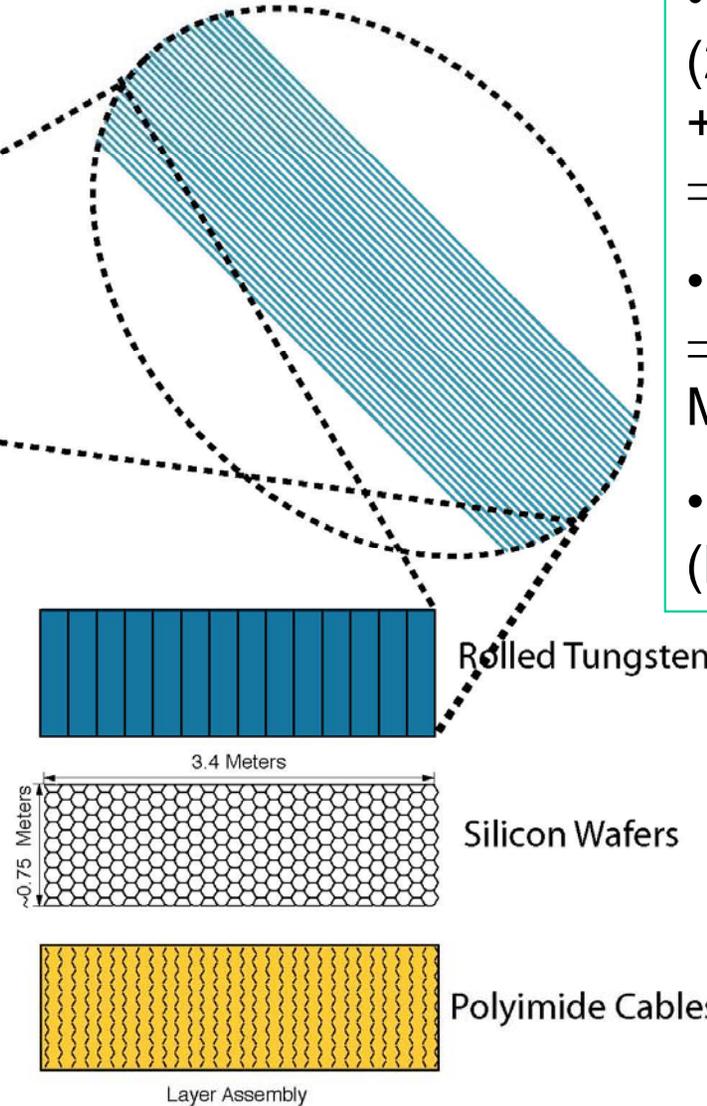
ECAL

Inner Tracker

1.25m



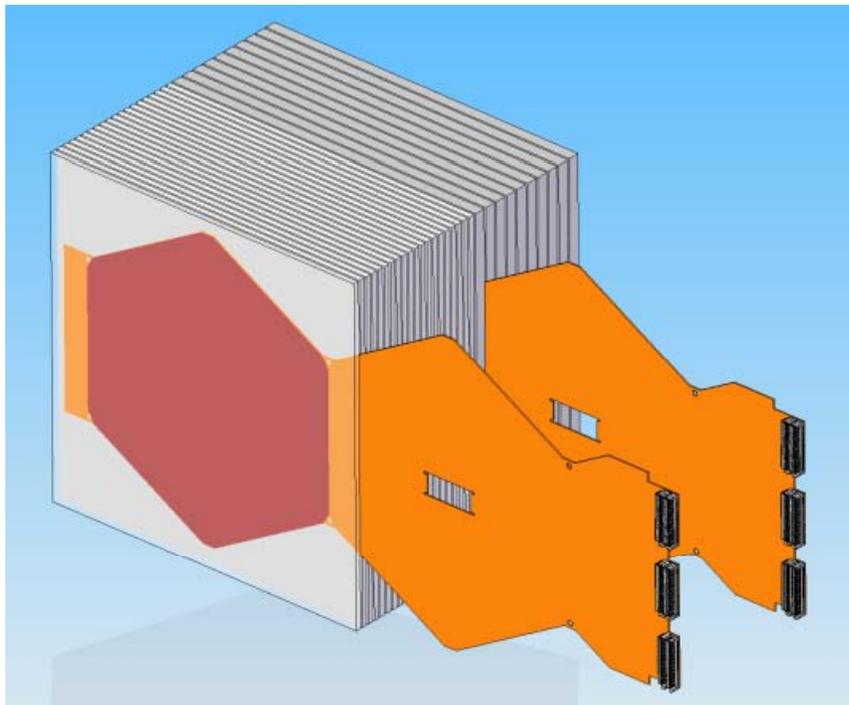
- longitudinal:
(20 layers x $5/7 X_0$)
+ (10 layers x $10/7 X_0$)
 $\Rightarrow 17\%/sqrt(E)$
- 1 mm readout gaps
 $\Rightarrow 13$ mm effective
Moliere radius
- 13 mm^2 pixels
(baseline)



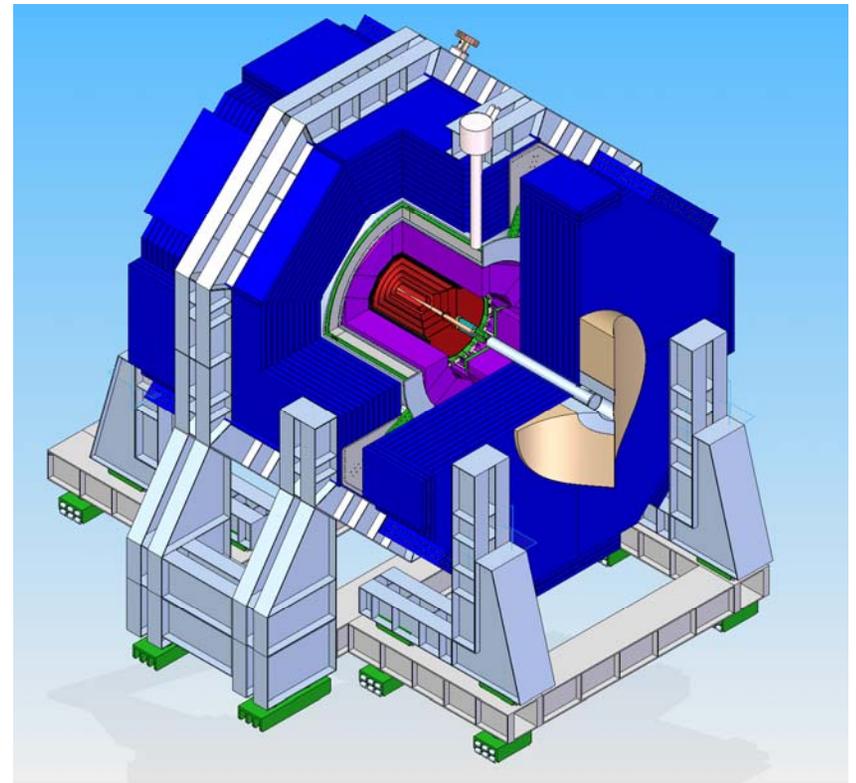
Transverse Segmentation $(3.6\text{mm})^2$
20 + 10 Longitudinal Samples
Energy Resolution $\sim 17\%/E^{1/2}$

Two intertwined goals

- Complete the R&D, build a test stack, and evaluate performance in a test beam.



- Fully integrate the design into SiD



R&D goals, status, plans – from ~1 year ago

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Status	<ul style="list-style-type: none"> • Sensors – OK • Tungsten – OK • KPiX – 512 channel chip to be evaluated. If ok, order 1024 KPiX. • KPiX-Si bumps: need to converge on technology – gold stud thermo-compress? • Flex cable – ok • Cable-Si connect: needs R&D – ACF? 	<p>Need the integrated tests first.</p> <p>Flex cable can be done separately; same for DAQ</p>	tbd
Plan	<ul style="list-style-type: none"> • Have 1024 KPiX and bumping technology by summer for combined testing in lab. (512 KPiX would be ok for initial combined tests.) • indium/solder bb as fallback for gold studs • Need to finalize cable-Si technology 	<p>If integrated tests look OK, begin planning for beam test. Assume SLAC beam for now.</p>	tbd

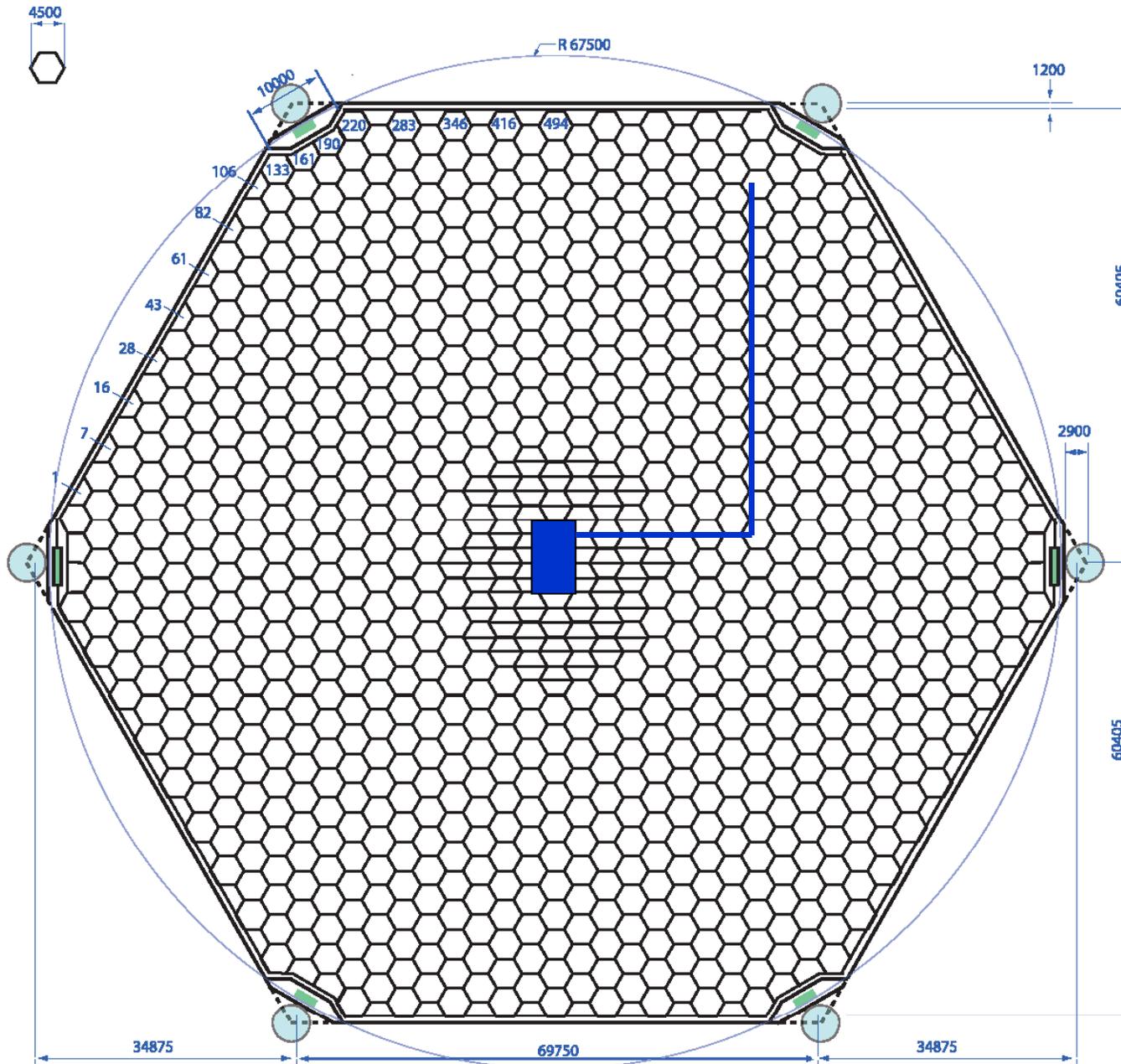
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v2 Si sensors – mid 2008



- 6 inch wafer
- 1024 13 mm² pixels
- improved trace layout and split pixels near KPiX to reduce capacitance
- 40 good + **20 NG** sensors in hand, Hamamatsu

KPiX ASIC and sample trace

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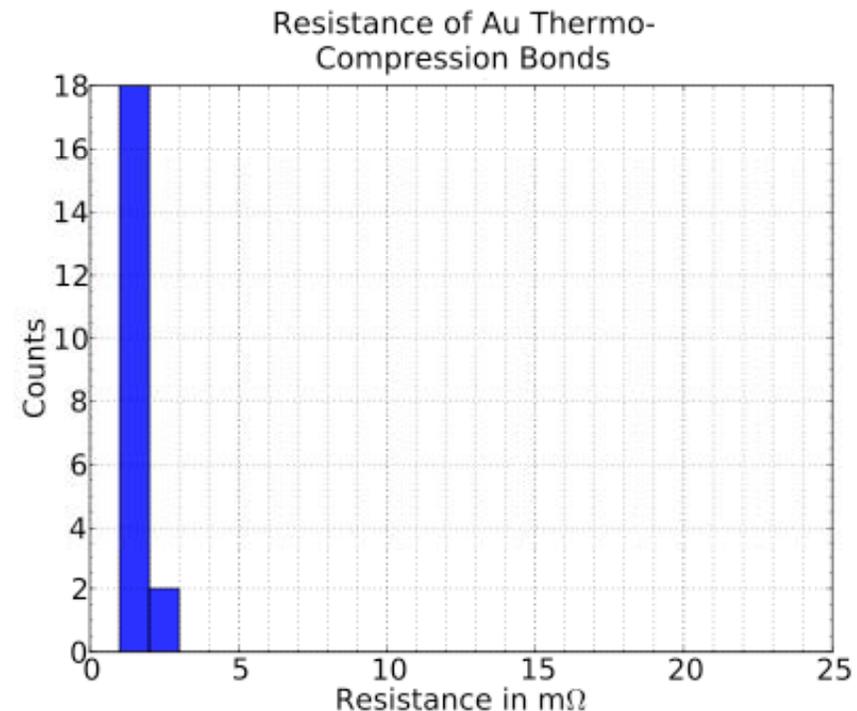
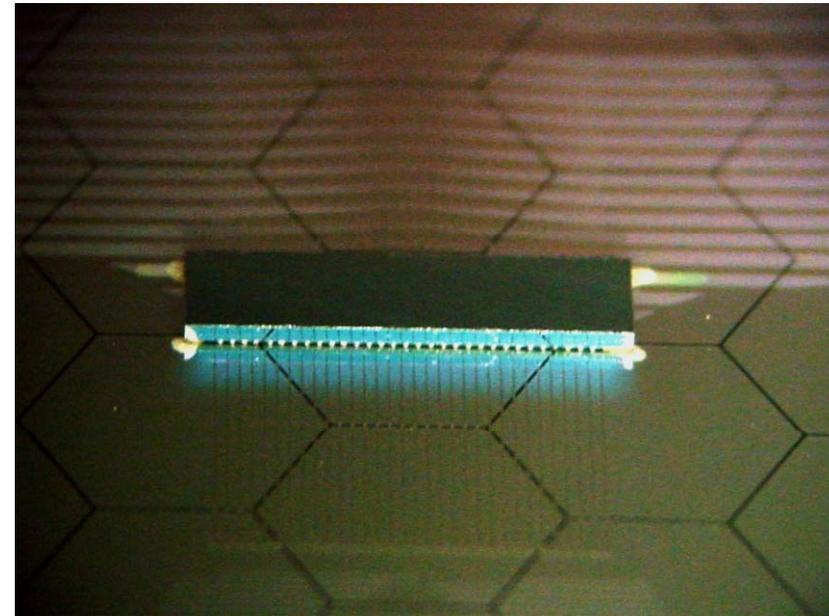
No!

Gold-Stud Thermo-compression Bonding

Appeared to be an ideal technique for bump-bonding with prototypes:

- Complete in-house capability.
- Good results obtained with dummy chips with bump resistances $<5\text{ m}\Omega$

- However, the same technique did not work for Hamamatsu sensor wafers because the oxide under the bump could not withstand the $\sim 160\text{g/bump}$ pressure. It was crushed resulting in shorts with buried traces.



Take n: Current plan for KPiX-sensor bb

- The new version of KPiX (1024) will have solder bumps placed on it by TSMC. (!!)
- These bumps are made using the C4 process -- the solder used is high temp Pb/Sn (95/5 %).
- We (Davis) are looking to acquire an oven capable of uniform and controlled re-flow of this solder at 320° C for bonding to sensors.

R&D goals, status, plans – from ~1 year ago

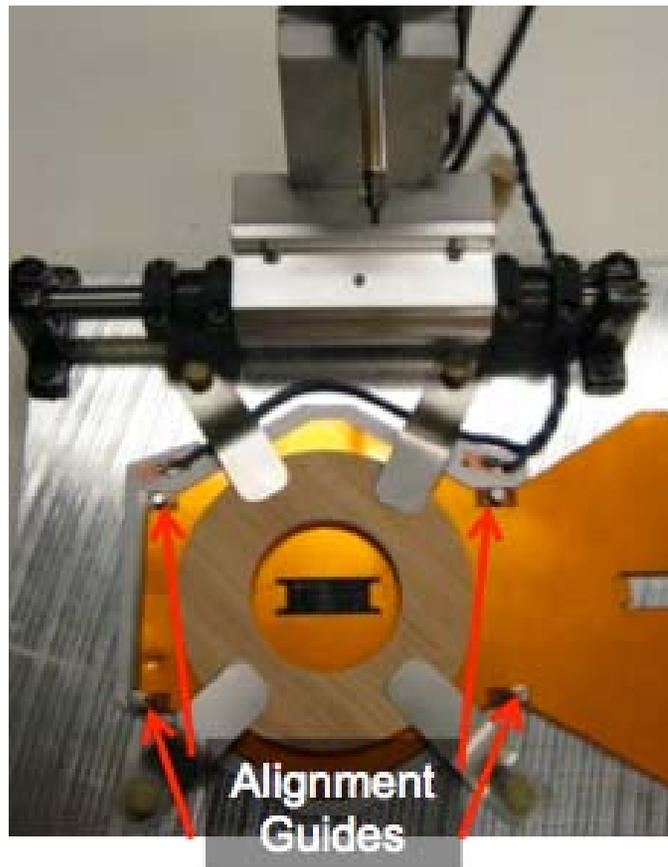
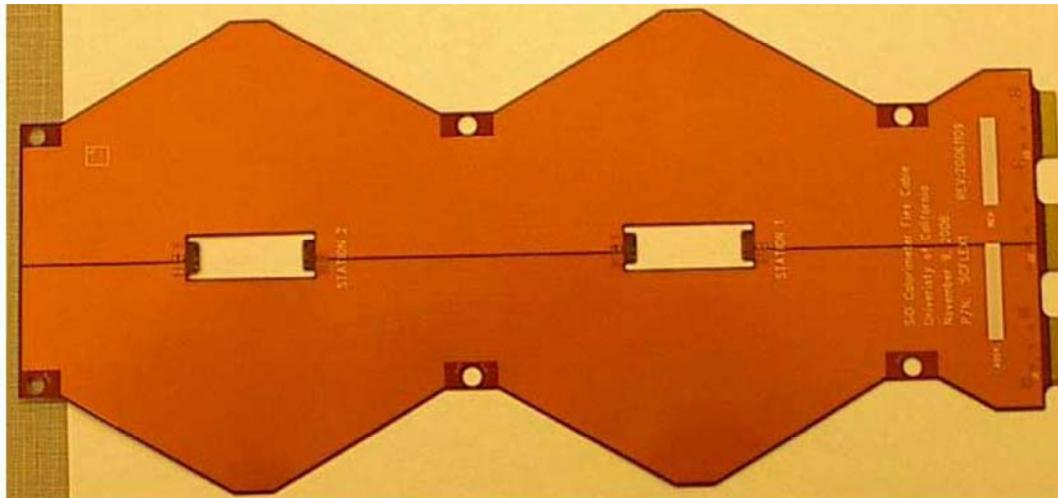
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maybe

Flex cables (Davis)

Flexcables

- “OK” for test stack
- Need to check longer ~1 m cables for SiD.



Sensor connection technology:

- ACF looks promising for large-scale production
- Solder bumps – current default
 - Placed using Davis setup
 - <180 C solder
 - Trials with dummy sensors started

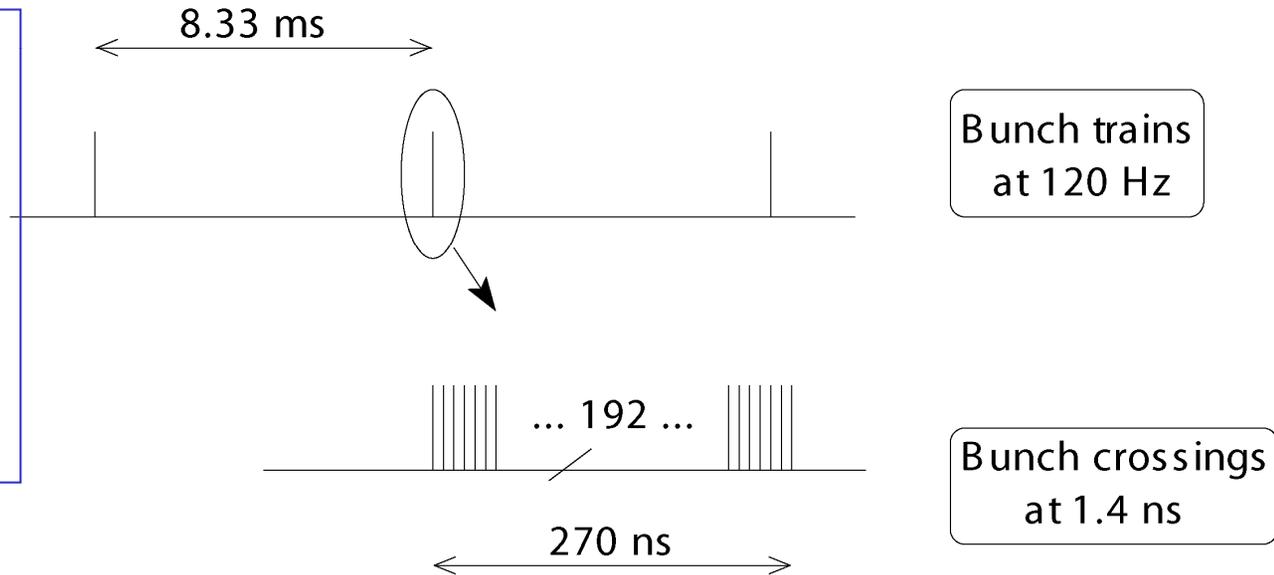
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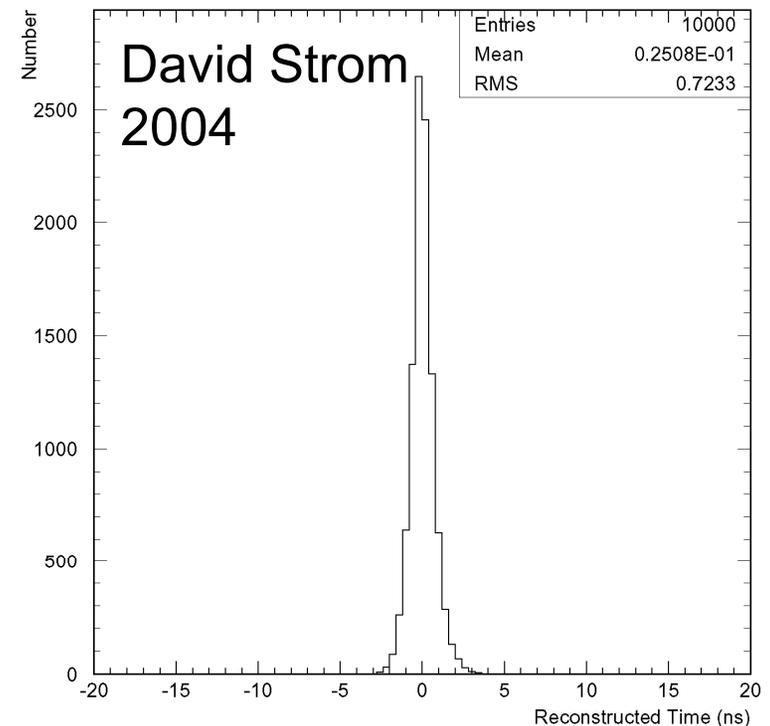
Our schedule is adjusting to that of the SLAC test beam !

(another) CLIC connection

For warm technology, we considered the ability to do time stamping with the Si/W ECal (ca 2004)



- The ECal was ~ identical to the current baseline Si/W, but with electronics designed for warm.
- A MIP hit would give ~5 ns timing resolution per Si layer
- Result is for simulation of single MIPs (30 layers) with 50 ns time constant in preamp. →



Summary

- **Steady technical progress with the R&D**
 - 1024-channel KPiX will be available in ~2 months
 - If bump-bonding technology works (!), we will be able to do the first system tests of the sensor+KPiX (winter 2011).
 - (Still) getting close to fabricating a test stack for a beam test.
 - (Still) compatible with schedule of SLAC test beam
- **For implementation in SiD, a number of issues to settle:**
 - Finalize the mechanical design for the barrel.
 - System tests: cooling, power delivery, correlated noise, etc.
 - Need a tiling scheme and mech. design for the endcaps
 - Reconstruction effort welcome, e.g. photon id in jets

Physics, ECal, LOI

Guiding principles: Measure all final states and measure with precision

- Multi-jet final states
 - π^0 measurement should not limit jet resolution
 - id and measure h^0 and h^\pm showers
 - track charged particles
- Tau id and analysis
- Photons
 - Energy resolution, e.g. $h \rightarrow \gamma\gamma$
 - Vertexing of photons ($\sigma_b \sim 1$ cm), e.g. for GMSB
- Electron id
- Bhabhas and Bhabha acollinearity
- Hermiticity

⇒ Imaging Ecalorimetry can do all this

